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| Search Notes  | Application/Control No. 10526520 | Applicant(s)/Patent Under Reexamination SCHULIST ET AL. |
| | Examiner Nguyen, Hai V | Art Unit 2618 |

| SEARCHED | | | |
|----------|----------|------------|----------|
| Class | Subclass | Date | Examiner |
| 370 | 335 | 12/22/2007 | HN |

| SEARCH NOTES | | |
|---|---------------------------|----------|
| Search Notes | Date | Examiner |
| EAST search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report) | 12/21/2007; 01/03/2008 | HN |
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| INTERFERENCE SEARCH | | | |
|---------------------|----------|------|----------|
| Class | Subclass | Date | Examiner |
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